



**Computing Platform Service Partner**

# **GENE-LN05**

## **Temperature/Humidity Test Report**

**Report NO: 10E020016**

**Issued by: Rex Chang / 06/10/2010**  
\_\_\_\_\_  
**Test Engineer Date**

**Reviewed by: Jansin / 06/10/2010**  
\_\_\_\_\_  
**Sr. Manager Date**

# Test item list

- |  |   |
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## Testing Result

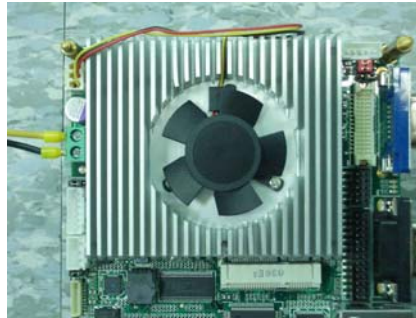
Num	Test item list	Result	Remark
1	Temp./humidity power on/off test	Pass	
2	Temperature variation operation test	Pass	
3	Cold start and hot start test	Pass	

# Configuration of EUT

## Test Product: GENE-LN05 A0.1

### Sample Configuration & Quantity Under Test:

1. CPU: Intel Atom D510 / 1.66GHz (Bios Ver.0.10)
2. Chipset: Intel PineView D/M + ICH8-M
3. VGA: Intel PineView D/M
4. Memory: Transcend 1GB / Qimonda HYB18T512800BF-3S / DDR2-667
5. CFD: PQI 32MB
6. 2.5" SATA HDD: Fujitsu MHY2060BH / 60GB
7. Test Software: Windows XP / Run PassMark Burn In Test Pro 4.0
8. AT Power Supply: Zippy SP2-4300F to ATX Mode
9. CPU Cooler:



**Test Date:** 06-08~09-2010

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference IEC 68-2-30 Testing procedures  
Test Db: Damp Heat Test

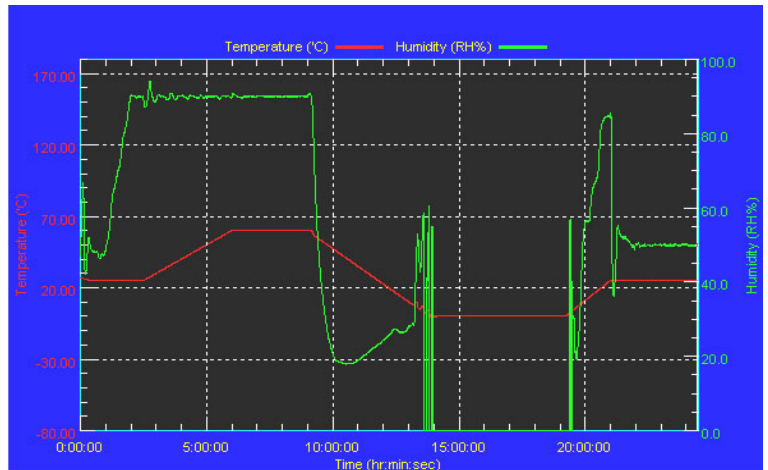
**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4H+-100  
Date of Calibration: 11/12/09  
Serial Number: 2582

**Temperature & Humidity Power On/Off Test:**

**Testing Specification:**

Step	Temperature (°C)	Humidity (%RH)	Duration (HH:MM)
1	25	50	00:30
2	25	50	00:30
3	25	90	01:00
4	25	90	00:30
5	60	90	03:30
6	60	90	03:00
7	0	0	04:50
8	0	0	05:23
9	25	50	01:47
10	25	50	03:00

**Test Curve:**



**Test Result:**

No problem was found during the temperature & humidity power on/off test.

Test Method	Actual	Successful	Failure rate	On time	Off Time
Power On/Off	1176/times	1176/times	0 %	38 Sec.	38 Sec.

Note: Failure rate need to under 0.2%.

**Test Date:** 06-09~10-2010

**Test Site:** AAEON QE Internal Lab.

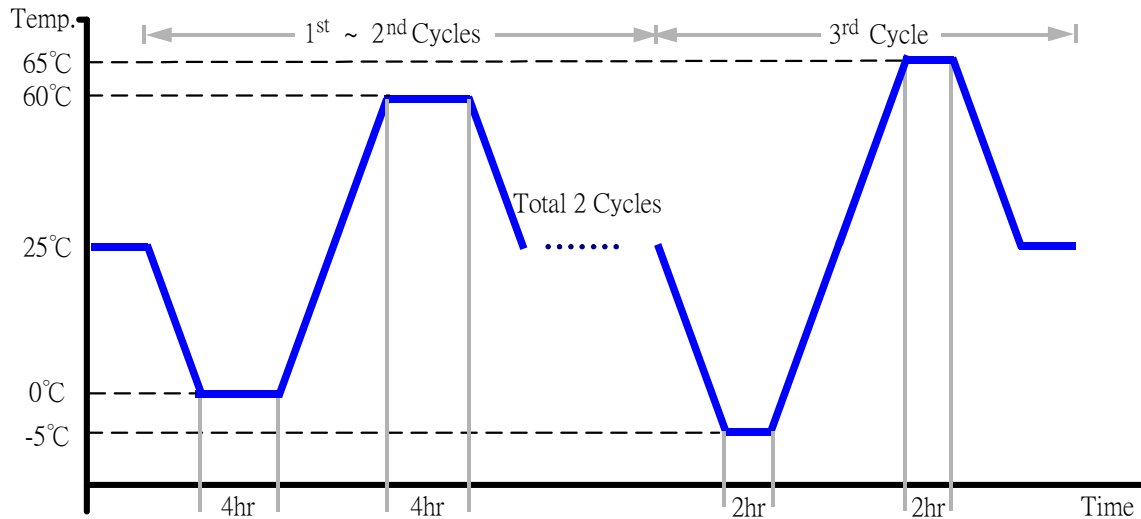
**Test Standard:** Reference IEC 68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4H+-100  
Date of Calibration: 11/12/09  
Serial Number: 2582

**Temperature & Humidity Cycle Test:**

1. Test Low Temperature: 0°C (1~2 cycles)  
-5°C (3<sup>rd</sup> cycle)
2. Test High Temperature: 60°C (1~2 cycles)  
65°C (3<sup>rd</sup> cycle)
3. Test dwell time: 4Hrs (1~2 cycles)  
2Hrs (3<sup>rd</sup> cycle)
4. Temperature slope: 2°C/min
5. Test cycle: 3 cycles
6. Test Environment Curve:



**Test Result:**

No problem was found during the temperature variation operation test.

# Cold start and hot start test

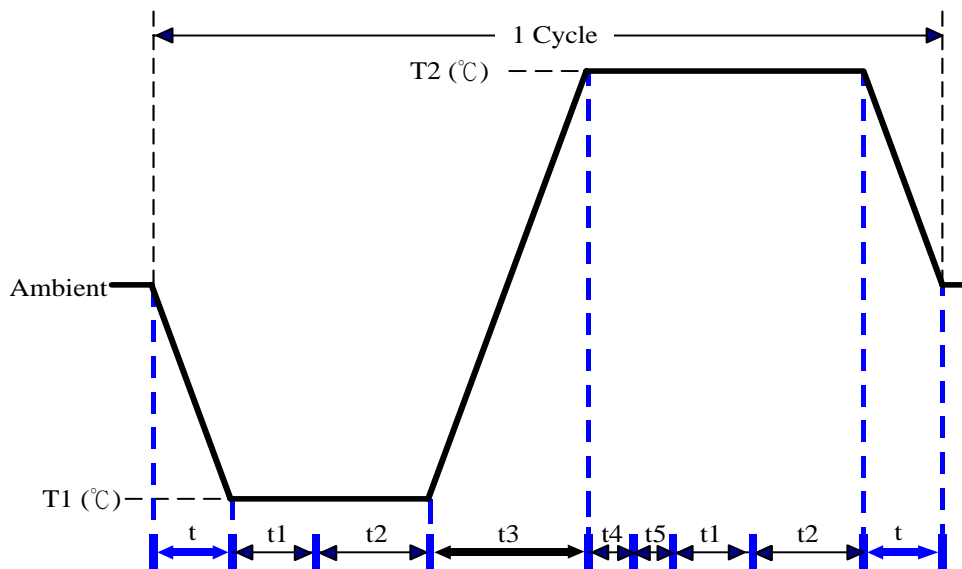
**Test Date:** 06-07-2010

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference IEC 68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4H+-100  
Date of Calibration: 11/12/09  
Serial Number: 2582

**Test Condition:**



Parameters	Description
T1	-5°C
T2	65°C
t1	1 hrs
t2	2 hrs
t4, t5	30 min
t, t3	2°C/min
n (Cycle)	1

t,t3 = temprature slope  
t, t1: Power Off  
t2: Power on/off test 10 times (on 2 min / off 5min)  
t3,t4: Run PassMark Burn In Test  
t5: Win XP Software restart test 2 times  
Test Software:Windows XP

**Test Result:**

- a. No problem was found during the cold start test.
- b. No problem was found during the hot start test.